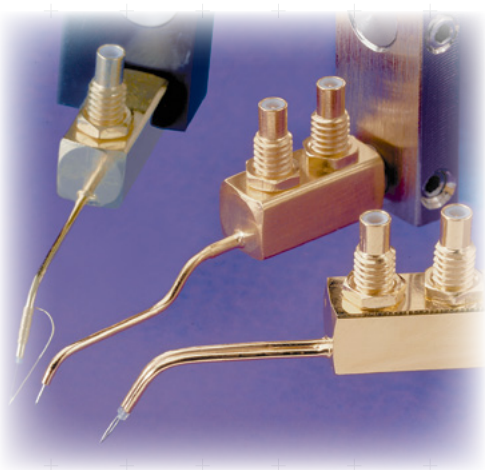


Cascade Microtech, Inc.

SPECIFICATION SHEET



Precision DC probe holder for advanced on-wafer process and device characterization

DCP-100

DC Probe Holder

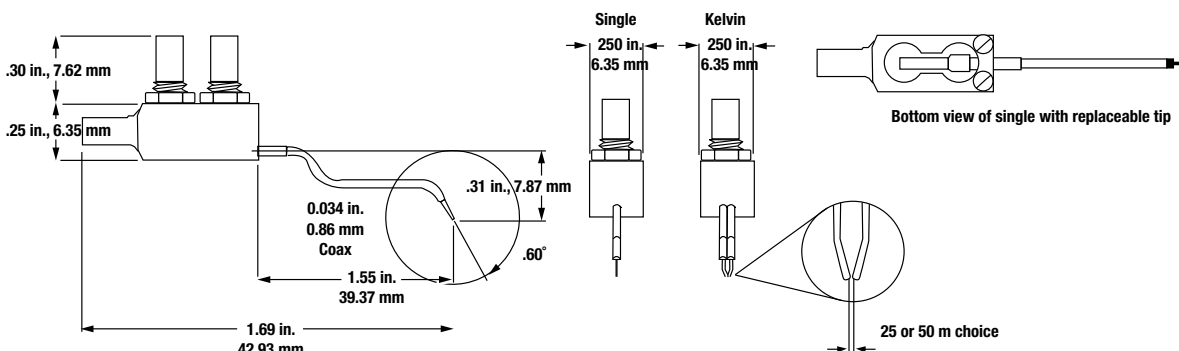
The DCP-100 series probe holder delivers the measurement accuracy needed for advanced on-wafer process and device characterization, as well as reliability testing. With superior guarding and shielding, DCP-100 series probe overcomes the performance limitations of non-coaxial needle probes.

For full-triaxial current/voltage measurements using combined signal, guard and shield cables, the DCP-100 probe should be used with Cascade Microtech's probing systems with MicroChamber®. The MicroChamber system provides full-EMI shielding around the wafer chuck and the probes, offering a fully-shielded, guarded, dark measurement environment. The triaxial connections from DC parametric semiconductor test instruments are then extended to the probe tip.

FEATURES AND BENEFITS

Low-noise electrical performance	Ultra-low, fA-level current and fF-level capacitance measurements
Field-replaceable coaxial probe tips	Tips can be easily replaced within minutes and guarantee fully-guarded measurements in fA and fF levels
Full-electrical guarding to probe tip	Enables full utilization of semiconductor parametric instrumentation performance

DIMENSIONS



Dimensions for the DCP 100 Probe Holder.

SPECIFICATIONS

Breakdown voltage	>500 V
Isolation resistance	>1 x 10E ¹³ Ω
Frequency response (3 dB)	150 MHz
Temperature range	-65°C to 150°C
Characteristic impedance	50 Ω
Tip material	Tungsten
Body material	Gold plated
Connector type	SSMC

ORDERING INFORMATION

DCP-100

Part Number	Description
Probe holders with replaceable tips	
DCP-105R	DC coaxial probe holder, single, replaceable tip (0.5 μm radius)
DCP-115R	DC coaxial probe holder, single, replaceable tip (1.5 μm radius)
DCP-150R	DC coaxial probe holder, single, replaceable tip (5.0 μm radius)
DCP-150GPR-50	DC coaxial probe holder, with ground needle (50 μm pitch)
Replaceable probe tips	
107-157	Replacement tips, 1.5 μm tip radius, box of 10
107-158	Replacement tips, 5 μm tip radius, box of 10
107-159	Replacement tips, 0.5 μm tip radius, box of 10
Non-replaceable dual-tip Kelvin coaxial probe tips	
DCP-150K-25	DC coaxial probe, Kelvin, 25 μm pitch, 5.0 μm radius tip
DCP-150K-50	DC coaxial probe, Kelvin, 50 μm pitch, 5.0 μm radius tip

© Copyright 2010 Cascade Microtech, Inc.
All rights reserved. Cascade Microtech and
MicroChamber are registered trademarks of
Cascade Microtech, Inc. All other trademarks
are the property of their respective owners.

Data subject to change without notice

DCP100-SS-0810

Cascade Microtech, Inc.
toll free: +1-800-550-3279
phone: +1-503-601-1000
email: cmi_sales@cmicro.com

Cascade Microtech GmbH
phone: +49-89-9090195-0
email: cmg_sales@cmicro.com

Cascade Microtech Japan
phone: +81-3-5615-5150
email: cmj_sales@cmicro.com

Cascade Microtech Shanghai
phone: +86-21-3330-3188
email: cmc_sales@cmicro.com

Cascade Microtech Singapore
phone: +65-6873-7482
email: cms_sales@cmicro.com

Cascade Microtech Taiwan
phone: +886-3-5722810
email: cmt_sales@cmicro.com